STQ3NK50ZR-AP
STD3NK50Z - STD3NK50Z-1

N-CHANNEL 500V - 2.8Ω - 2.3A TO-92/DPAK/IPAK
Zener-Protected SuperMESH™ MOSFET

Table 1: General Features

TYPE	V_{DSS}	$R_{DS(on)}$	I_D	Pw
STQ3NK50ZR-AP	500 V	3.3 Ω	0.5 A	3 W
STD3NK50Z	500 V	3.3 Ω	2.3 A	45 W
STD3NK50Z-1	500 V	3.3 Ω	2.3 A	45 W

- TYPICAL R_{DS}(on) = 2.8Ω
- EXTREMELY HIGH dv/dt CAPABILITY
- ESD IMPROVED CAPABILITY)
- 100% AVALANCHE TESTED
- NEW HIGH VOLTAGE BENCHMARK
- GATE CHARGE MINIMIZED

DESCRIPTION

The SuperMESH™ series is obtained through an extreme opyimization of ST's well established strip based PowerMESH™ layout. In addition to pushing on-resistance significatly down, special care is taken to ensure a very good dv/dt capability for the most demanding application. Such series complements ST full range of high voltage MOSFETs icluding revolutionary MDmesh™ products

APPLICATIONS

- AC ADAPTORS AND BATTERY CHARGERS
- SWITH MODE POWER SUPPLIES (SMPS)
- LIGHTING

Figure 1: Package

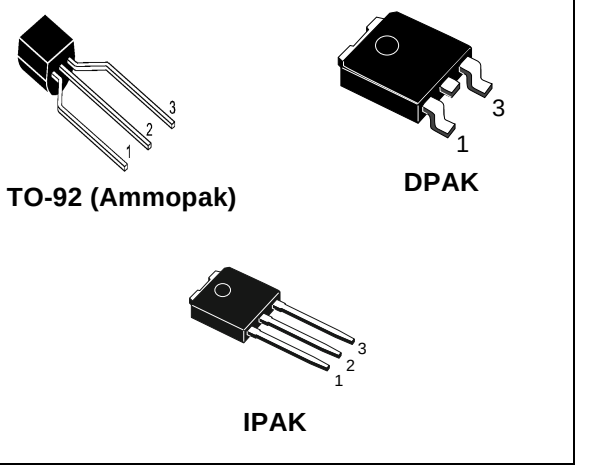

Figure 2: Internal Schematic Diagram

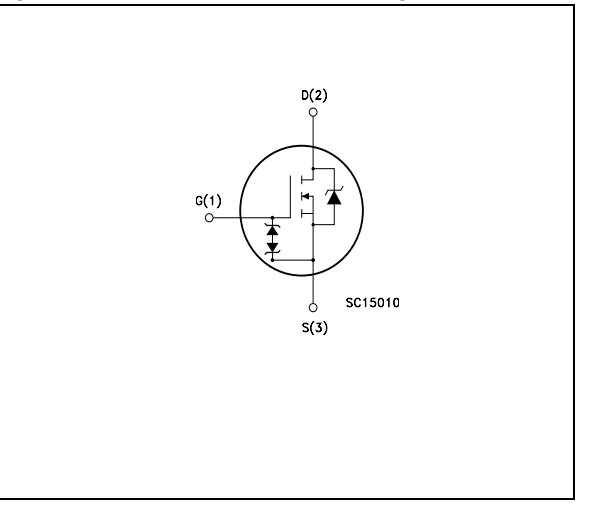

Table 2: Order Coder

SALES TYPE	MARKING	PACKAGE	PACKAGING
STQ3NK50ZR-AP	Q3NK50ZR	TO-92	AMMOPAK
STD3NK50Z	D3NK50Z	DPAK	TAPE & REEL
STD3NK50Z-1	D3NK50Z	IPAK	TUBE

Table 3: Absolute Maximum ratings

Symbol	Parameter	Value		Unit
		DPAK/IPAK	TO-92	
V_{DS}	Drain-source Voltage (V_{GS} = 0)	500		V
V_{DGR}	Drain-gate Voltage (R_{GS} = 20 kΩ)	500		V
V_{GS}	Gate- source Voltage	±30		V
I_D	Drain Current (continuous) at T_C = 25°C	2.3	0.5	A
I_D	Drain Current (continuous) at T_C = 100°C	1.45	0.32	A
I_{DM} (•)	Drain Current (pulsed)	9.2	2	A
P_{TOT}	Total Dissipation at T_C = 25°C	45	3	W
	Derating Factor	0.36	0.025	W/°C
$V_{ESD(G-S)}$	Gate source ESD (HBM-C=100 pF, R= 1.5KΩ)	2000		V
dv/dt (1)	Peak Diode Recovery voltage slope	4.5		V/ns
T_j T_{stg}	Operating Junction Temperature Storage Temperature	-55 to 150		°C

(•) Pulse width limited by safe operating area
(1) $I_D \leq 2$ di/dt ≤ 200A/µs, $V_{DD} \leq V_{(BR)DSS}$

Table 4: Thermal Data

		DPAK	IPAK	TO-92	Unit
Rthj-case	Thermal Resistance Junction-case Max	2.77		--	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	50 (#)	100	120	°C/W
Rthj-lead	Thermal Resistance Junction-lead Max	--	--	40	°C/W
T_l	Maximum Lead Temperature For Soldering Purpose	275		260	°C

(#) When mounted on 1inch² FR4, 2 Oz copper board.

Table 5: Avalanche Characteristics

Symbol	Parameter	Max. Value	Unit
I_{AR}	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T_j max)	2.3	A
E_{AS}	Single Pulse Avalanche Energy (starting T_j = 25 °C, $I_D = I_{AR}$, V_{DD} = 50 V)	120	mJ

Table 6: GATE-SOURCE ZENER DIODE

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV_{GSO}	Gate-Source Breakdown Voltage	Igs=± 1mA (Open Drain)	30			V

PROTECTION FEATURES OF GATE-TO-SOURCE ZENER DIODES

The built-in-back-to-back Zener diodes have specifically been designed to enchance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

ELECTRICAL CHARACTERISTICS (T_{CASE} =25°C UNLESS OTHERWISE SPECIFIED)

Table 7: On/Off

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source Breakdown Voltage	I_D = 1 mA, V_{GS} = 0	500			V
I_{DSS}	Zero Gate Voltage Drain Current (V_{GS} = 0) Zero Gate Voltage Drain Current (V_{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating, T_C = 125 °C			1 50	µA µA
I_{GSS}	Gate-body Leakage Current (V_{DS} = 0)	V_{GS} = ± 20V			±10	µA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 50 µA	3	3.75	4.5	V
$R_{DS(on)}$	Static Drain-source On Resistance	V_{GS} = 10V, I_D = 1.15 A		2.8	3.3	Ω

Table 8: Dynamic

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g_{fs} (1)	Forward Transconductance	V_{DS} = 15 V, I_D = 1.15 A		1.5		S
C_{iss} C_{oss} C_{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V_{DS} = 25V, f = 1 MHz, V_{GS} = 0		280 42 8		pF pF pF
$C_{oss\ eq.}$ (3)	Equivalent Output Capacitance	V_{GS} = 0V, V_{DS} = 0V to 400 V		27.5		pF
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	V_{DD} = 250 V, I_D = 1.15 A R_G = 4.7Ω V_{GS} = 10 V (see Figure 19)		8 13 24 14		ns ns ns ns
Q_g Q_{gs} Q_{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V_{DD} = 400 V, I_D = 2.3 A, V_{GS} = 10V (see Figure 22)		11 2.5 5.6	15	nC nC nC

Table 9: Source Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{SD} I_{SDM} (2)	Source-drain Current Source-drain Current (pulsed)				2.3 9.2	A A
V_{SD} (1)	Forward On Voltage	I_{SD} = 2.3 A, V_{GS} = 0			1.6	V
t_{rr} Q_{rr} I_{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	I_{SD} =2.3 A, di/dt = 100 A/µs V_{DD} = 40V, T_j = 25°C (see Figure 20)		250 745 6		ns µC A
t_{rr} Q_{rr} I_{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	I_{SD} =2.3A, di/dt = 100 A/µs V_{DD} = 40V, T_j = 150°C (see Figure 20)		300 960 6.2		ns µC A

Note: 1. Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %.
2. Pulse width limited by safe operating area.
3. $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.

Figure 3: Safe Operating Area For TO-92

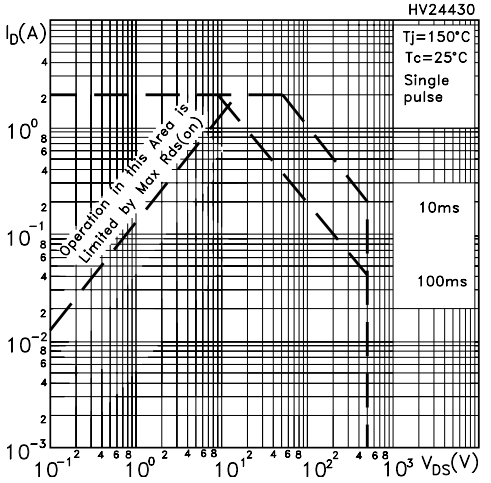

Figure 4: Safe Operating Area For DPAK / IPAK

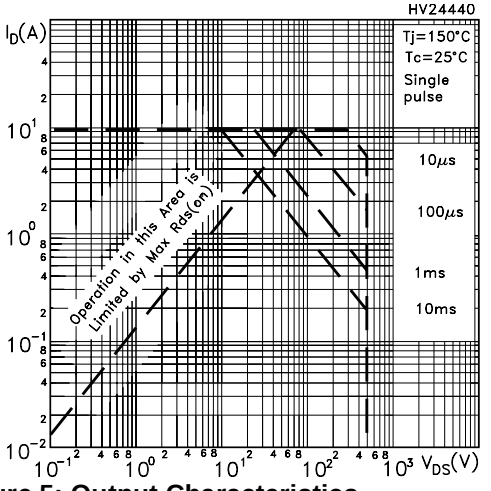

Figure 5: Output Characteristics

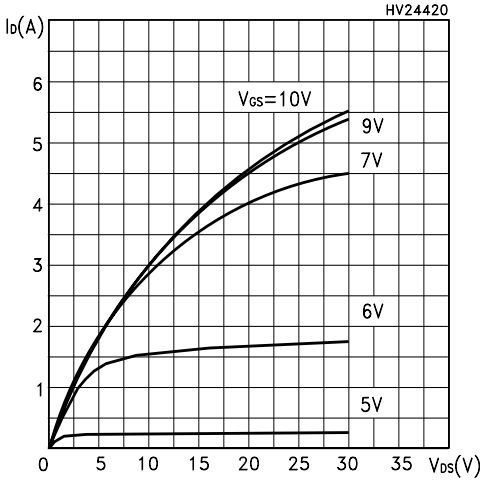

Figure 6: Thermal Impedance TO-92

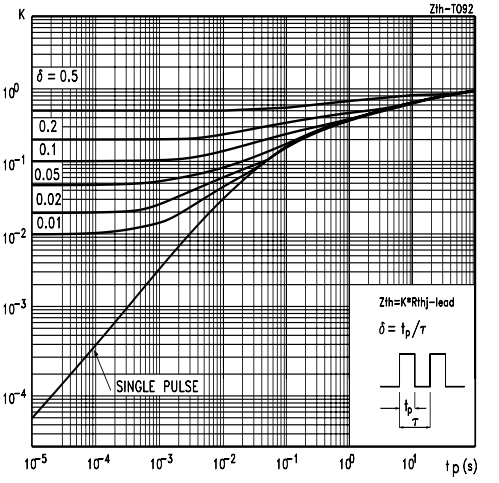

Figure 7: Thermal Impedance For DPAK / IPAK

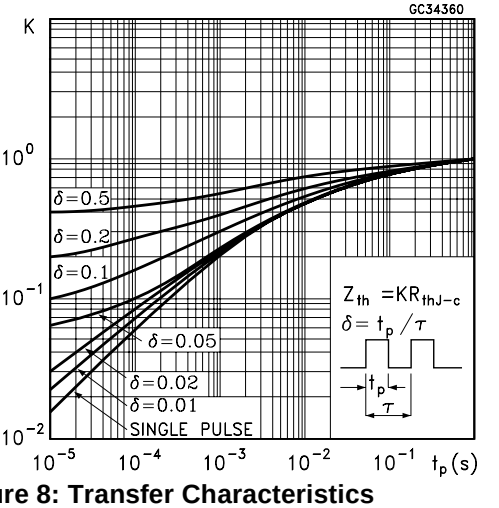

Figure 8: Transfer Characteristics